


Search Notes 	Application/Control No. 10574286	Applicant(s)/Patent Under Reexamination OIKAWA ET AL.
	Examiner CEDRIC CHAN	Art Unit 1797

SEARCHED			
Class	Subclass	Date	Examiner
422	99,102,104,255,261,266,292	8/21/2010	CC
134	117,150	8/21/2010	CC
216	83,84,100,8,10	8/21/2010	CC
118	400,404,427	8/21/2010	CC

SEARCH NOTES		
Search Notes	Date	Examiner
inventor name search (PALM)	2/5/2010	CC
inventor name search (EAST)	2/13/2010	CC
searched US/Foreign databases -- EAST/USPat,OCR,PGPub,EPO,JPO,Derwent	2/13/2010	CC
assignee search (EAST)	8/21/2010	CC
updated class, inventor search & updated keyword search of US/For databases (see EAST History)	8/21/2010	CC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/C. C./
Examiner,Art Unit 1797